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	Application No.	Applicant(s)	7
Notice of Allowability	10/768,163 Examiner	TAKEUCHI ET AL.	
	Faye Polyzos	2878	
The MAILING DATE of this communication at All claims being allowable, PROSECUTION ON THE MERITS herewith (or previously mailed), a Notice of Allowance (PTOL NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATEN of the Office or upon petition by the applicant. See 37 CFR 1	S IS (OR REMAINS) CLOSED ir -85) or other appropriate commu T RIGHTS. This application is s	nthis application. If not include unication will be mailed in due	ed course. THIS
1. \boxtimes This communication is responsive to <u>2 February 2004</u> .			
2. ☑ The allowed claim(s) is/are <u>1-6</u> .		•	
3. 🖾 The drawings filed on <u>02 February 2004</u> are accepted	by the Examiner.		
 4. Acknowledgment is made of a claim for foreign priorit a) All b) Some* c) None of the: 1. Certified copies of the priority documents I 2. Certified copies of the priority documents I 	nave been received.		
3. Copies of the certified copies of the priority	, ,		tion from the
International Bureau (PCT Rule 17.2(a)).		,	
* Certified copies not received:		•	
Applicant has THREE MONTHS FROM THE "MAILING DA' noted below. Failure to timely comply will result in ABANDO THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		a reply complying with the red	quirements
5. A SUBSTITUTE OATH OR DECLARATION must be so INFORMAL PATENT APPLICATION (PTO-152) which	ubmitted. Note the attached EXA gives reason(s) why the oath or	AMINER'S AMENDMENT or Note declaration is deficient.	OTICE OF
6. CORRECTED DRAWINGS (as "replacement sheets")	must be submitted.		
(a) 🔲 including changes required by the Notice of Drafts	person's Patent Drawing Reviev	v (PTO-948) attached	
1) ☐ hereto or 2) ☐ to Paper No./Mail Date	<u></u> .		
(b) ☐ including changes required by the attached Exami Paper No./Mail Date	ner's Amendment / Comment or	in the Office action of	
Identifying indicia such as the application number (see 37 Cleach sheet. Replacement sheet(s) should be labeled as such			back) of
 DEPOSIT OF and/or INFORMATION about the dattached Examiner's comment regarding REQUIREME 	eposit of BIOLOGICAL MATE NT FOR THE DEPOSIT OF BIO	ERIAL must be submitted. N DLOGICAL MATERIAL	Note the
Attachment(s)	_		
1. ☑ Notice of References Cited (PTO-892)		formal Patent Application (PT	D-152)
2. Notice of Draftperson's Patent Drawing Review (PTO-9		ummary (PTO-413), Mail Date	
 Information Disclosure Statements (PTO-1449 or PTO/S Paper No./Mail Date <u>2/2/04</u> 	6B/08), 7. ☐ Examiner's	Amendment/Comment	
 Examiner's Comment Regarding Requirement for Depo 	sit 8. ⊠ Examiner's	Statement of Reasons for Allo	wance
of Biological Material	9. Other	<u>-</u> •	

EXAMINER'S STATEMENT OF REASONS FOR ALLOWANCE

Allowable Subject Matter

Claims 1-6 are allowed.

2. The following is an examiner's statement of reasons for allowance:

Regarding independent claim 1, the prior art does not disclose or fairly suggest of a method of evaluating a piezoelectric field whereby utilizing a relationship between the piezoelectric field and energy level corresponding to peak position of absorption band to obtain piezoelectric field strength.

The examiner notes that while it is known in the art for modulation spectroscopy, (i.e. photoreflectance), to measure electric fields in semiconductor microstructures (sample) wherein a probe beam is the only illumination and the modulation measurement is between two finite electric fields: dark field and illuminated field (see for example *Shen et al – "Franz-Keldysh Oscillations in Modulation Spectroscopy" –* Figs. 3(a)(b), 7, 24 and pp. 2151 and 2168), the prior art does not fairly suggest of evaluating peak position of absorption band between piezoelectric field and energy level to obtain piezoelectric field strength.

Regarding independent claim 6, the prior art does not disclose or fairly suggest of a method of evaluating a piezoelectric field whereby utilizing a relationship between the piezoelectric field and energy level corresponding to peak position of absorption band to obtain piezoelectric field strength.

The examiner notes that while it is known in the art for modulation spectroscopy, (i.e. photoreflectance), to measure absorption spectrum of a sample by irradiating the

sample, while placed on a turntable, with infrared light at a predetermined angular frequency (see for example *Czabaffy et al* – *US 4,632,549* – Figs. 1-2 and col. 6, line 41-68 and col. 8, lines 41-67), the prior art does not fairly suggest of evaluating peak position of absorption band between piezoelectric field and energy level to obtain piezoelectric field strength.

The remaining claims 2-5 are allowed based on their dependency

3. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

- 4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
- 5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Faye Polyzos whose telephone number is 571-272-2447. The examiner can normally be reached on Monday thru Friday from 7:30 AM to 4:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Dave Porta can be reached on 571-272-2444. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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6. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

FP

SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 2800